

# Statement of Conformity

## Best Laboratory Co., Ltd.

No. 336, Ba Lian RD., Sec. 1, Hsi Chih City, Taipei Hsien, Taiwan, R.O.C.  
Telephone: 886-2-2646-2899 Facsimile: 886-2-2646-2870

### *EMC Certificate*

**Applicant** : Advantech Co., Ltd.  
**Address** : Fl.4, No. 108-3, Ming-Chuan Road,  
Shing-Tien City, Taipei, Taiwan, R.O.C.  
**Equipment** : Biscuit 486CPU-133 FSB-66 clock  
all-in-one LAN/VGA CPU card  
**Model** : PCM-9340

Has fully complied with the requirements set out in the council directive on the approximation of the law of the members states relating to Electromagnetic Compatibility Directive (89/336/EEC). For the evaluation regarding EMC, the following standards were applied:

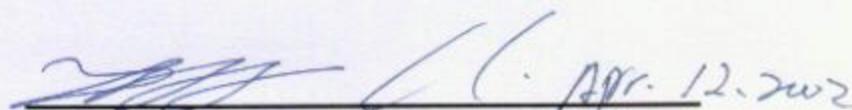
EMI: EN 50081-2:1993 -> EN 55011:1999, EN 61000-3-2:2000, EN 61000-3-3:1995

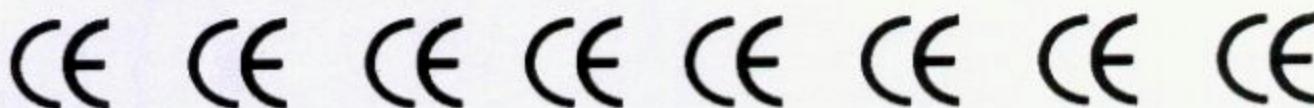
EMS: EN 61000-6-2:1999 -> EN 61000-4-2:1998, EN 61000-4-3:1998,  
EN 61000-4-4:1995, EN 61000-4-5:1995,  
EN 61000-4-6:1996, EN 61000-4-8:1993,  
EN 61000-4-11:1994,

**The date of the measurement: Apr. 10, 2002**

**The date of the certification signed: Apr. 12, 2002**

**The number of EMC Certificate: CER-A01-CE-656**  
**Test Laboratory**

  
Quality Department Manager: JEFF CHIU



This verification is based on a single evaluation of one sample of above-mentioned products. It does not imply any assessment of the whole production and does not permit the use of the logo of the test laboratory.

# EMC TEST REPORT

Applicant : Advantech Co., Ltd.

Equipment : Biscuit 486CPU-133 FSB-66 clock  
all-in-one LAN/VGA CPU card

Model : PCM-9340

# Test Report Certification

## Best Laboratory Co., Ltd.

No. 336, Ba Lian Rd., Sec. 1, Hsi Chih City, Taipei Hsien, Taiwan, R.O.C.  
Tel: 886-2-2646-2899 Fax: 886-2-2646-2870

Applicant : Advantech Co., Ltd.  
Address : Fl.4, No. 108-3, Ming-Chuan Road,  
Shing-Tien City, Taipei, Taiwan, R.O.C.  
Equipment : Biscuit 486CPU-133 FSB-66 clock all-in-one LAN/VGA CPU card  
Model : PCM-9340  
Device's Class : Class A Device  
Measurement Standard : EN 50081-2/1993, EN 61000-6-2/1999  
Measurement Procedure : EN 55011/1999, EN 61000-3-2/2000, EN 61000-3-3/1995,  
EN 61000-4-2/1998, EN 61000-4-3/1998, EN 61000-4-4/1995,  
EN 61000-4-5/1995, EN 61000-4-6/1996, EN 61000-4-8/1993  
EN 61000-4-11/1994  
Operating Voltage : By PC  
Test Result : **Compliance** (Detail showed in the test report)  
Sample Received : Mar. 26, 2002  
Test Date : Apr. 10, 2002  
Report Number : RE-A01-CE-656  
Test Firm : No. 336, Ba Lian Rd., Sec. 1,  
Hsi Chih City, Taipei Hsien, Taiwan, R.O.C.

Remark:

- (1) The test report is only relating to the sample tested
- (2) The test report shall not be reproduced except in full, without the written approval of Best Laboratory Co., Ltd.
- (3) The test result of this report are traceable to the national or international standards.

Prepared : Ivan Hsieh  
IVAN HSIEH

Approved : Jeff Chiu ( Title: Quality Department Manager )  
JEFF CHIU

Date Issued : Apr. 12, 2002

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# 1. General Information

## 1.1 EUT Description

Applicant : Advantech Co., Ltd.

Address : Fl.4, No. 108-3, Ming-Chuan Road,  
Shing-Tien City, Taipei, Taiwan, R.O.C.

Equipment : Biscuit 486CPU-133 FSB-66 clock all-in-one LAN/VGA CPU card

Model : PCM-9340

Device's Class : Class A Device

Operation Voltage : By PC

Output Ports :

- HDD Connector : Connected with one hard disk driver, via one rainbow cable which length is 26 cm long, non-shielded, no ferrite bead.
- Parallel Connector: The Parallel connector is connected with one 25-pin D-Sub connector installed on case via one rainbow cable, 30 cm long, non-shielded, no ferrite bead.
- Serial Connector : The Serial connector is connected with one 9-pin D-Sub connector installed on case via one rainbow cable, 30 cm long, non-shielded, no ferrite bead.
- LAN Port : Via one RJ-45 cable, 30 meters long, non-shielded, no ferrite bead, to the far-end HUB.
- Serial port : Connected with one RS-232 cable, 1.8 meters long, non-shielded, no ferrite bead, left un terminal.
- PS/2 Port : Connected with one PS/2 keyboard and PS/2 mouse which length is 120 cm long, non-shielded, no ferrite bead, via a Y data cable which length is 80 cm long, non-shielded, no ferrite bead.
- Monitor Port : Connected with one monitor which data cable is 1.8 meters long, shielded, with ferrite bead.
- Power Connector : Connected with the switching power supply, which outlet connector is connected with the AC power source, via one bunch of power cable which is 20 cm long. non-shielded, no ferrite bead.

## 1.2 Test System Detail

**Monitor : HITACHI**

Model No. : CM771U  
Serial No. : V0E001074  
FCC ID : DoC Approval  
BSMI : 3882A707  
Power Type : 100-240VAC, 50/60Hz, 1.5A, Switching  
Power Cord : 180cm long, non-shielded, no ferrite bead.  
Data Cable : 120cm long, shielded, with ferrite bead  
Backshell : Metal  
Connected Port : VGA Port

**Keyboard : HP (Pavilion)**

Model No. : SK-2506  
Serial No. : C0006002889  
FCC ID : DoC Approval  
BSMI : 3882A375  
Power Type : By PC  
Data Cable : 180cm long, shielded, no ferrite bead  
Backshell : Metal  
Connected Port : PS/2 Keyboard Port

**Mouse : Logitech**

Model No. : M-S48a  
Serial No. : N/A  
FCC ID : JNZ201213  
BSMI : 4882A001  
Power Type : By PC  
Data Cable : 120cm long, non-shielded, no ferrite bead  
Backshell : Metal  
Connected Port : PS/2 Mouse Port

**Modem : ACEEX**

Model No. : XDM-9624  
Serial No. : 0017884  
FCC ID : IFAXDM-9624  
Power Type : 230VAC, 50Hz / 9VAC, 1A  
Power Core : 1.9meters long, non-shielded, no ferrite bead  
Data Cable : RS-232, shielded, 1.2meters long, no ferrite bead  
RJ11C x 2, 7' long, non-shielded, no ferrite bead  
Backshell : Metal  
Connected Port : Serial Port.

**Printer : Epson**

Model No. : P950  
Serial No. : BW9Y113923  
FCC ID : DoC Approval  
BSMI : 3872P001  
Power Type : 230VAC, 50Hz, 0.4A  
Power Core : 165cm long, non-shielded, no ferrite bead  
Data Cable : 120cm long, shielded, no ferrite bead  
Backshell : Metal  
Connected Port : Parallel Port

**Case : Advantech**

Model No. : MBPC-200-5820  
Serial No. : TPB0002012  
Power Cord : 180cm long, non-shielded, no ferrite bead.

**Hard disk driver : IBM**

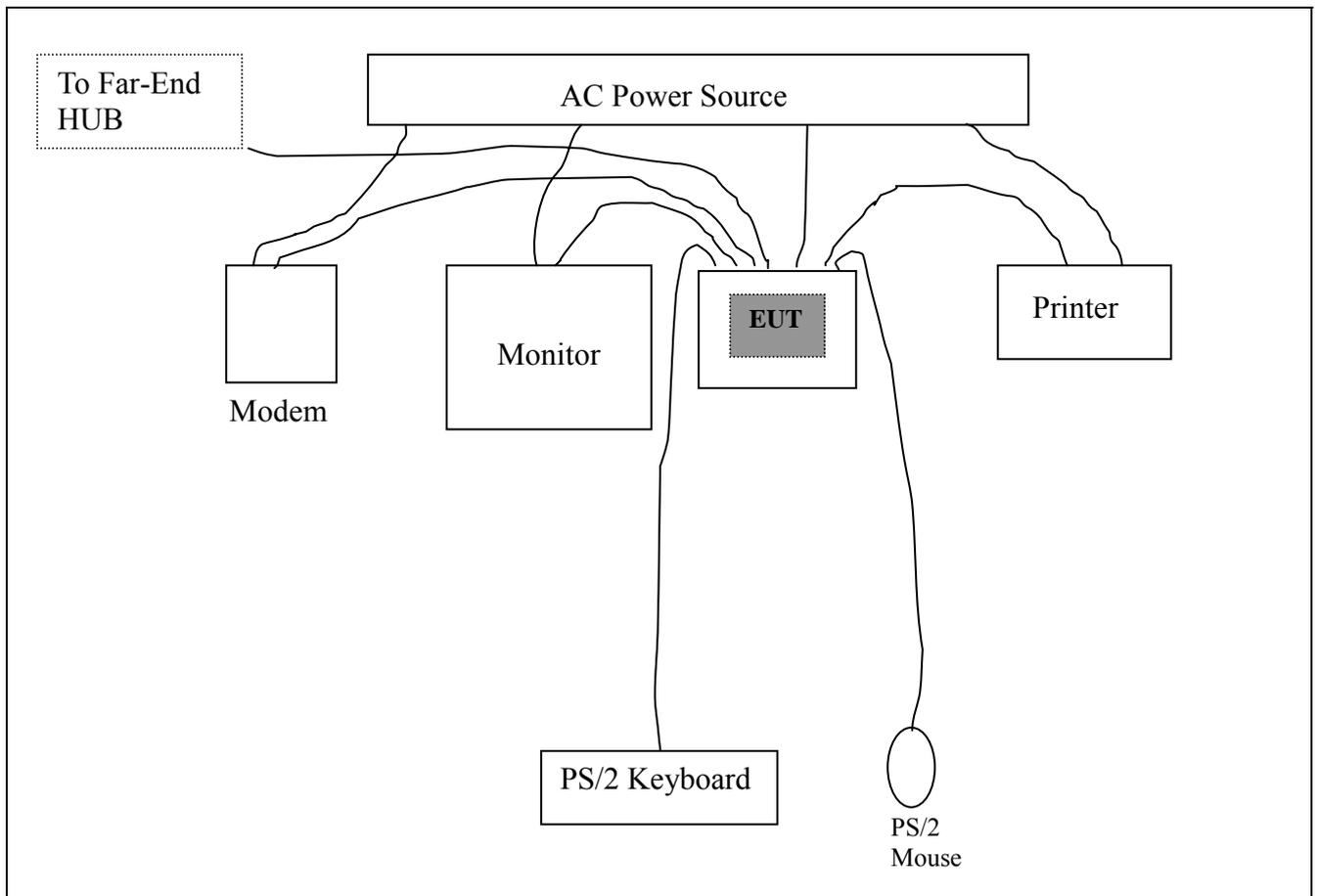
Model No. : DJSA-210  
Serial No. : 07N5643  
FCC ID : DoC Approval  
BSMI : 3892I133  
Power Type : 115/230VAC, 60/50Hz, 5A, Switching  
Power Cord : 26cm long, non-shielded, no ferrite bead.  
Capacity : 6.00 Gigabyte

### 1.3 EUT Configuration

- (1) The HDD connector of EUT is connected with one hard disk driver, via one rainbow cable.
- (2) The Parallel connector of EUT is connected with one 25-pin D-Sub connector installed on case, via one rainbow cable.
- (3) The Serial connector of EUT is connected with one 9-pin D-Sub connector installed on case, via one rainbow cable.
- (4) The PS/2 port of EUT is connected with one PS/2 keyboard and PS/2 mouse, via a Y data cable.
- (5) The serial port of EUT is connected with one RS-232 cable left un terminal.
- (6) The monitor port of EUT is connected with one monitor.
- (7) The LAN port of EUT is connected with the HUB located in far-end.
- (8) The ATX power port of EUT is connected with the inlet port of one switching power supply that connected with the AC power source.

(\*\*PS: Please refers to the Photograph\*\*)

#### Drawing of Configuration



## 1.4 EUT Exercise Software

The testing software is provided by the applicant.

It is designed to exercise the EUT in a manner similar to a typical use. The testing software will link two LAN cards to transmit data, via two RJ-45 jacks. The software will send an “ H “ pattern to the monitor and the “ H “ pattern will be shown on the monitor. The software will also send an “ H “ pattern to the printer and the “ H “ pattern will be printer out at the printer. The software will also send the data to the modem and the modem will response to the EUT. The HDD will continuously working sequence in the “ Write-Read-Delete “ mode. At the same time, the mouse and keyboard will be in continuously self-test mode and responded to the EUT. The software will enable all functions of EUT.

## 1.5 Test Performed

Conducted emissions were invested over the frequency range from 0.15MHz to 30MHz using a receiver which bandwidth is set at 9KHz.

Radiated emissions were invested over the frequency range from 30MHz to 1000MHz using a receiver which bandwidth is set at 120KHz. Radiated measurement was performed at distance that from an antenna to EUT is 10 meters.

The testing result of pretest was shown out that the “Transmitting/Receiving” mode is worse than the “ Standby “ mode. So, the final measurement was made on the “Transmitting/Receiving” mode.

There are three video resolution testing modes when the tests and the measurements was performed: “640 X 480 MHz”, “800 X 600 MHz”, “1024 X 768 MHz”.

Because the specification of the LAN port of EUT, the two testing modes will be invested: 10MHz and 100MHz.

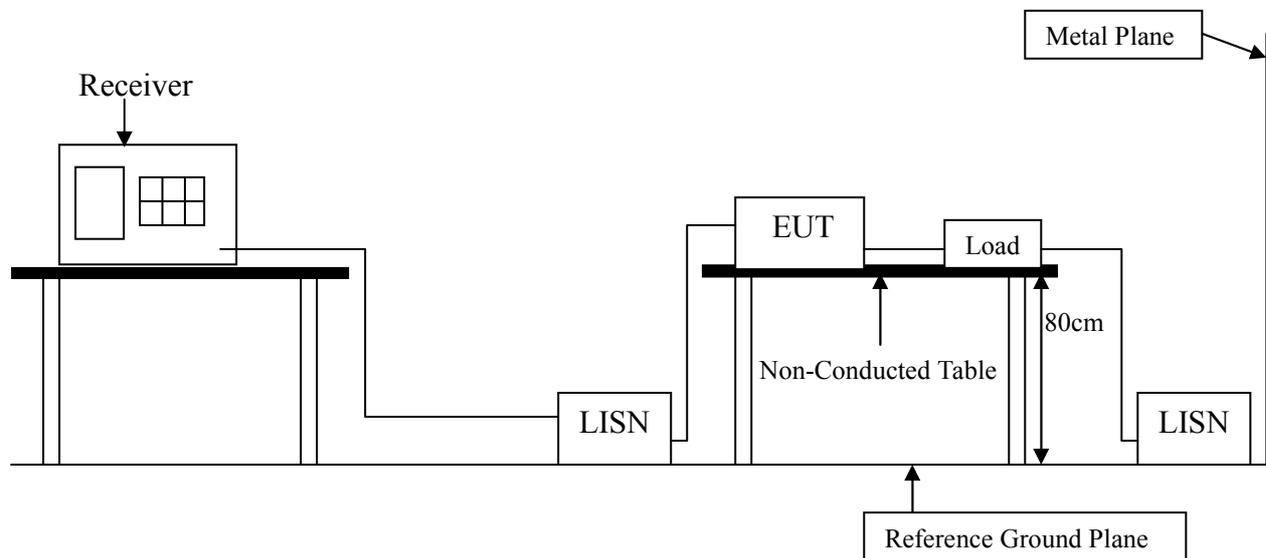
## 2 Conducted Emission Measurement at Mains Port

### 2.1 Test Equipment

No.	Instrument	Manufacture	Model	Serial No.	Last Calibrate
1.	LISN (EUT)	Rolf Heine	NNB-2/16Z	99084	May 14, 2001
2.	LISN (AXE)	Rolf Heine	NNB-2/16Z	99086	May 14, 2001
3.	EMI Receiver	Rohde & Schwarz	ESI 7	830154/001	June 27, 2001
4.	50Ω Terminator	Amphenol	46650-51	N/A	Dec. 10, 2001
5.	RF Cable	Belden	M17/158	MIL-C-17	Jan. 20, 2002

Remark: All equipment upon which need to calibrated are with calibration period of one year.

### 2.2 Test Set-Up



### 2.3 Limit

Frequency	Limit (dBμV)			
	Class A		Class B	
	Quasi Peak	Average	Quasi Peak	Average
0.15 ~ 0.50	79	66	66 ~ 56	56 ~ 46
0.50 ~ 5.0	73	60	56	46
5.0 ~ 30.0	73	60	60	50

Remark: In the above table, the tighter limit applies at the band edges.

## 2.4 Test Procedure

The EUT and simulators are connected to the main power through a line impedance stabilization network (LISN). It provides a 50 ohm / 50  $\mu$ H coupling impedance for the measuring equipment. The peripheral devices are also connected to the main power through a LISN that provides a 50 ohm / 50  $\mu$ H coupling impedance with 50 ohm termination. (Please refers to the block diagram of the test setup and photograph.)

Both sides of DC line are checked for the maximum conducted emission interference. In order to find the maximum emissions, the relating positions of equipment and all of the interference cables must be changed according to EN 55011/1999 regulation: The measurement procedure on conducted emission interference.

The resolution bandwidth of the field strength meter ( Rohde & Schwarz ) is set at 9KHz.

## 5 Test Specification

According to the EN 55011/1999

## 2.6 Test Result

The emissions that come from the EUT were below the specified limits. The worst case of conducted emissions measurement are shown in the appendix A. The acceptance criterion was met and the EUT has pass the measurement.

## 2.7 Deviation from the Test Method

No Deviation.

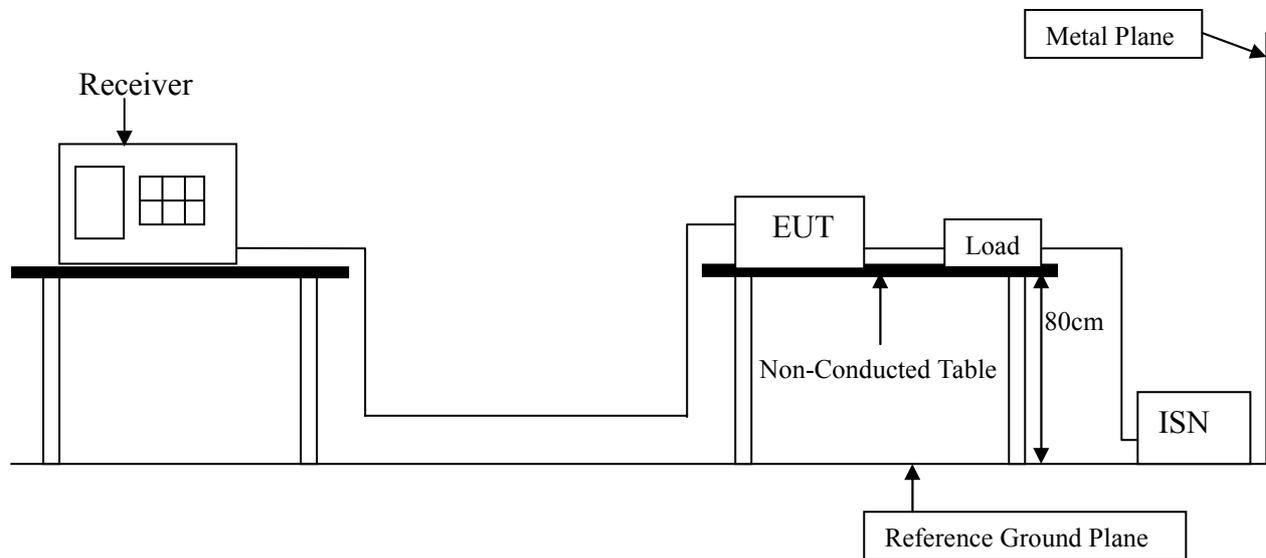
### 3 Conducted Emission Measurement at Telecommunication Port

#### 3.1 Test Equipment

No.	Instrument	Manufacture	Model	Serial No.	Last Calibrate
1.	ISN (EUT)	Shaffner	ISN T411	200102-010	Feb. 24, 2002
2.	ISN Adapter	Shaffner	ADS T444	200102-032	Feb. 24, 2002
3.	EMI Receiver	Rohde & Schwarz	ESI 7	830154/001	Nov 22, 2001
4.	50Ω Terminator	Amphenol	46650-51	N/A	Dec. 10, 2001
5.	RF Cable	Belden	M17/158	MIL-C-17	Jan. 20, 2002

Remark: All equipment upon which need to calibrated are with calibration period of one year.

#### 3.2 Test Set-Up



#### 3.3 Limit

Class A ITE

Frequency	Limit (dBμV)		Limit (dBμA)	
	Voltage Limits		Currents Limits	
MHz	Quasi Peak	Average	Quasi Peak	Average
0.15 ~ 0.50	97 ~ 87	84 ~ 74	53 ~ 43	40 ~ 30
0.50 ~ 5.0	87	74	43	30
5.0 ~ 30.0	87	74	43	30

Remark: In the above table, the tighter limit applies at the band edges.

## Class B ITE

Frequency	Limit (dB $\mu$ V)		Limit (dB $\mu$ A)	
	Voltage Limits		Currents Limits	
MHz	Quasi Peak	Average	Quasi Peak	Average
0.15 ~ 0.50	84 ~ 74	74 ~ 64	40 ~ 30	30 ~ 20
0.50 ~ 5.0	74	64	30	20
5.0 ~ 30.0	74	64	30	20

Remark: In the above table, the tighter limit applies at the band edges.

### 3.4 Test Procedure

The characteristics of LCL of ISN:

150KHz ~ 1.5MHz: 80dB  $\pm$  3dB

1.5MHz ~ 30MHz: (80dB to 55dB)  $\pm$  3dB, decreasing linearly with the logarithm of the frequency

The ISN is connected to the communication port through a cable. The common-mode terminating impedance of this ISN observed from the communication ports when the disturbance is measured shall apply with the regulation. The ISN shall be inserted between the EUT and the auxiliary equipment that is required for operation of the EUT through the signal cable

Two sides of telecommunication ports are checked for the maximum conducted emission interference. In order to find the maximum emissions, the relating positions of equipment and all of the interference cables must be changed according to EN 55011/1999 regulation: The measurement procedure on conducted emission interference.

### 3.5 Test Specification

According to the EN 55011/1999

### 3.6 Test Result

N / A

### 3.7 Deviation from the Test Method

N / A

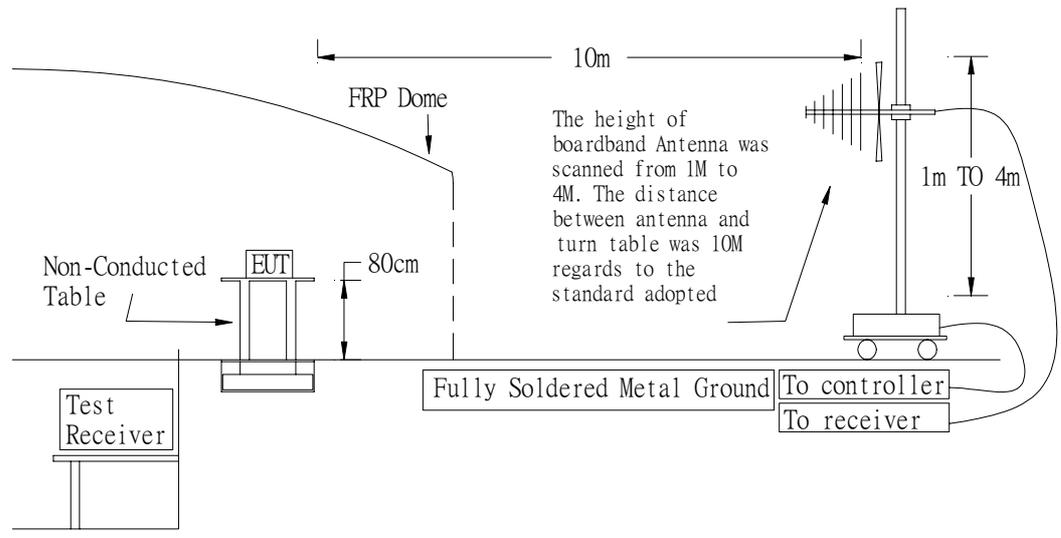
## 4. Radiated Emission Measurement

### 4.1 Test Equipment List

No.	Instrument	Manufacture	Model	Serial No.	Last Calibrate
11.	Antenna	Mess-Elektronik	VULB 9160	9160-3078	Jan. 19, 2002
2.	EMI Receiver	Rohde & Schwarz	ESI 7	830154/001	June 27, 2001
3.	RF Cable	Adventest	AD-N-CA-01	2000-0220	Jan. 20, 2002
4.	OATS	Bestlab	N/A	OATS#1	May 28, 2001

Remark: All equipment upon which need to calibrated are with calibration period of one year.

### 4.2 Test Setup



### 4.3 Limit

Frequency MHz	Class A		Class B	
	Distance (Meter)	Limit (dB $\mu$ V/m)	Distance (Meter)	Limit (dB $\mu$ V/m)
30 ~ 230	10	40	10	30
230 ~ 1000	10	47	10	37

Remark: In the above table, the tighter limit applies at the band edges

### 4.4 Test Procedure

The EUT and its simulators are placed on turn table, non-ducted and wooden, which is 0.8 meter above ground. The turn table rotates 360 degree to determine the position of the maximum emission level. The EUT was positioned such that distance from antenna to the EUT is 10 meters.

The antenna is moved up and down between 1 meter to 4 meter to receive the maximum emission level.

Both horizontal and vertical polarization of the antenna are set on measurement. In order to find the maximum emission, all of the interference cables must be manipulated according to EN 55011/1999 regulation: the test procedure of the radiated emission measurement.

The bandwidth set on the field strength is 120KHz when the frequency range is below 1GHz

### 4.5 Test Specification

According to EN 55011/1999

### 4.6 Test Result

The emissions that come from the EUT was below the specified limits. The worst case of conducted emissions measurement are shown in the appendix A. The acceptance criterion was met and the EUT has pass the measurement.

### 4.7 Deviation from the Test Method

No Deviation.

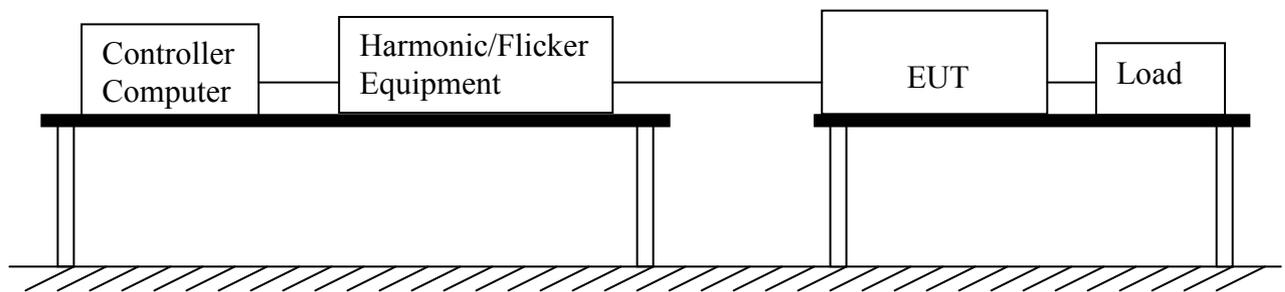
## 5. Power Harmonic and Voltage Fluctuation Measurement

### 5.1 Power Harmonic and Voltage Fluctuation Test Equipment List

No.	Instrument	Manufacture	Model	Serial No.	Last Calibrate
1.	H/F Test System	EMC Partner	Harmonic-1000	325807	May. 10, 2001

Remark: All equipment upon which need to calibrated are with calibration period of 1 year.

### 5.2 Test Setup



### 5.3 Limit of Harmonic Current

Limit of Harmonic Currents

Harmonic Order	Maximum Permissible Harmonic Current (Ampere)	Harmonic Order	Maximum Permissible Harmonic Current (Ampere)
Odd Harmonic		Even Harmonic	
3	2.30	2	1.08
5	1.14	4	0.43
7	0.77	6	0.30
9	0.40	8 ≤ n ≤ 40	0.23 x 8/n
11	0.33		
13	0.21		
15 ≤ n ≤ 39	0.15 x 15/n		

## 5.4 Test Procedure

The EUT is supplied in series with power analyzer from a power source has the same normal voltage and frequency as the rated supply voltage and the equipment under test. The rated voltage at the supply voltage of EUT of 0.94 times and 1.06 times shall be performed.

## 5.5 Test Specification

According to EN 61000-3-2/2000, EN 61000-3-3/1995

## 5.6 Test Result

N / A

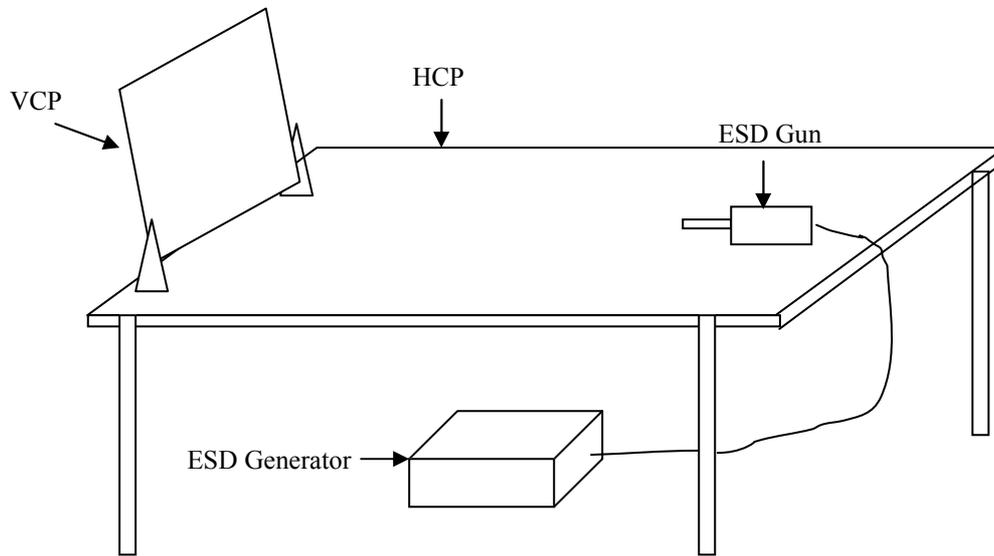
## 6 .Electrostatic Discharge (ESD)

### 6.1 Test Equipment List

No.	Instrument	Manufacture	Model	Serial No.	Last Calibrate
1.	ESD Emulator	Noiseken	ESS-100L	0199C02380	Mar. 02, 2002

Remark: All equipment upon which need to calibrated are with calibration period of one year.

### 6.2 Test Setup



### 6.3 Test Level

Item	Environment	Unit	Test Specification	Performance Criteria
Enclosure Room	Electrostatic Discharge	KV(Charge Voltage)	8 (Air Discharge) 4 (Contact Discharge)	B

## 6.4 Test Procedure

Direct applicant of discharge to the EUT:

Contact discharge was applied only to the conducted surfaces of the EUT.

Air discharge was applied only to the non-conductive surfaces of the EUT.

When the measurement was taken, The ESD discharger was performed in single discharge. For the single discharge time between successive single discharges will keep on one second. It was at least ten single discharges with positive and negative at the same selected pointed. The selected pointed, which was performed with electrostatic discharge, was marked on the red label on the EUT.

Indirect applicant of discharge to the EUT:

Vertical Coupling Plane (VCP)

The coupling plane, of dimensions 0.5m x 0.5m, is placed parallel to , and positioned at a distance 0.1m from, the EUT, with the discharge electrode touching the coupling plane.

The four faces of the EUT will be performed with electrostatic discharge. It was at least ten single discharges with positive and negative at the same selected point.

Horizontal Coupling Plane (HCP)

The coupling plane is placed under the EUT. The generator shall be positioned vertically at a distance of 0.1m from the EUT, with the discharge electrode touching the coupling.

The four faces of the EUT will be performed with electrostatic discharge. It was at least ten single discharges with positive and negative at the same selected pointed.

## 6.5 Test Specification

According to EN 61000-4-2/1998

## 6.6 Test Result

The measurement of the electrostatic discharge was investigated and the test result was shown on the Appendix A. The acceptance criterion was met and the EUT has passed the measurement.

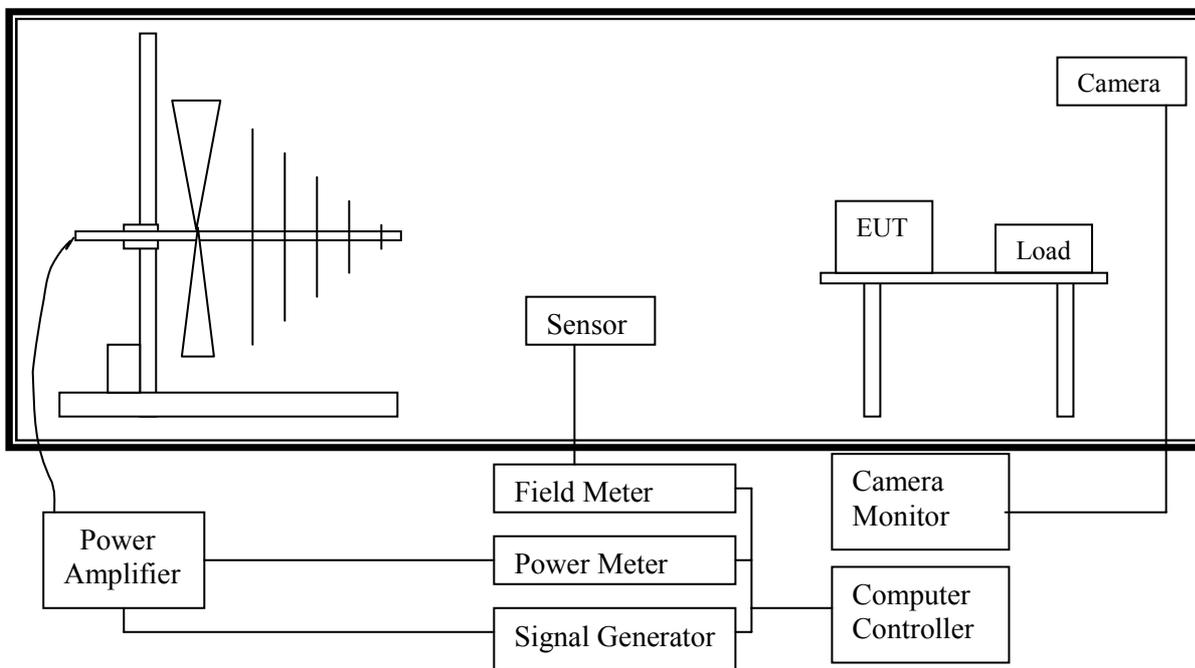
## 7. Radiated Susceptibility (RS)

### 7.1 Test Equipment List

No.	Instrument	Manufacture	Model	Serial No.	Last Calibrate
1.	Signal Generator	Rohde & Schwarz	SMY 02	845069/018	May 02, 2001
2.	Amplifier	Amplifier Research	100W1000M1A	20638	May 01, 2001
3.	Field Monitor	Amplifier Research	FM 2000	20391	Mar 03, 2002

Remark: All equipment upon which need to calibrated are with calibration period of one and half year.

### 7.2 Test Setup



### 7.3 Test Level

Item	Environment	Unit	Test Specification	Performance Criteria
Enclosure Room				
	Radio –Frequency	MHz	80 ~ 1000	A
	Electromagnetic Field	V/m (unmodulated, rms)	10	
	Amplitude Modulated	%AM (1KHz)	80	

## 7.4 Test Procedure

The EUT and load, which are placed on a wooden table that the height is 0.8 meter above ground, are placed with one coincident with the calibration plane such that the distance from antenna to the EUT is 3 meters.

Both horizontal and vertical polarization of the antenna position and four sides of the EUT are set on measurement.

In order to judge the EUT performance, a CCD camera is used to monitor the situation of EUT. All the scanning conditions are as follows:

Condition of Test	Remarks
EN 61000-4-3/1998	
1. Field Strength	10V/M; Level 3
2. Radiated Signal	AM 80% modulated with 1KHz
3. Scanning Frequencies	80MHz ~ 1000MHz
4. Dwell Time	3 seconds
5. Frequency step size $\Delta f$	1%
6. The rate of swept of frequency	$1.5 \times 10^{-3}$ decades/s

## 7.5 Specification

According to EN 61000-4-3/1998

## 7.6 Test Result

The measurement of the radiated susceptibility was investigated and the test result was shown on the appendix A. The acceptance criterion was met and the EUT has passed the measurement.

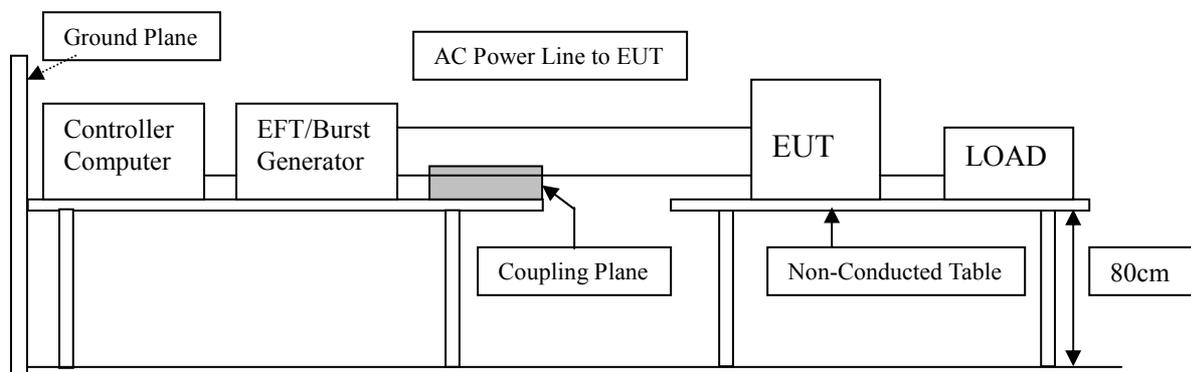
## 8 Electrical Fast Transient/Burst (EFT/B)

### 8.1 Test Equipment List

No.	Instrument	Manufacture	Model	Serial No.	Last Calibrate
1.	EMC Test System	EMC Partner	Transient-1000	TR1000-341	Aug 15, 2001
2.	Absorbing Clamp	EMC Partner	Transient-1000	CNEFT1000-176	Aug 15, 2001

Remark: All equipment upon which need to calibrated are with calibration period of one year.

### 8.2 Test Setup



### 8.3 Test Level

Item	Environment	Unit	Test Specification	Performance Criteria
Ports for signal Lines and Control Lines				B
	Fast Transients Common Mode	KV (Peak)	1	
		Tr/Ts (ns)	5/50	
		Rep. Frequency (KHz)	5	
DC Input and DC Output Power Ports				B
	Fast Transients Common Mode	KV (Peak)	2	
		Tr/Ts (ns)	5/50	
		Rep. Frequency (KHz)	5	
Input and Output AC Power Ports				B
	Fast Transients Common Mode	KV (Peak)	2	
		Tr/Ts (ns)	5/50	
		Rep. Frequency (KHz)	5	
Functional Earth Ports				B
	Fast Transients Common Mode	KV (Peak)	1	
		Tr/Ts (ns)	5/50	
		Rep. Frequency (KHz)	5	

## 8.4 Test Procedure

The EUT and load are placed on a wooden table that is 0.8meter height above a metal ground plane dimension is 1m x 1m and thickness is at least 0.2mm. It also projected beyond the EUT by at lease 0.1meter on all sides.

For Input and Output AC power or DC Input and DC Output Power Ports:

The EUT is connected with the power mains through a coupling device that directly couples the EFT interference signal.

Each of the line and nature conductors is impressed with burst noise for 1 minute.  
For Functional Earth Port:

The EUT is connected to the power mains through a coupling device that directly couples the EFT interference signal.

The protective earth line (PE) is impressed with burst noise for 1 minute.

The length of power cord between the coupling device and the EUT shall be 1 meter.  
For signal Lines and Control Lines Test:

The EFT interference signal is through a coupling clamp device couples to the signal and control lines of the EUT with burst noise for 1 minute.

## 8.5 Test Specification

According to EN 61000-4-4/1995

## 8.6 Test Result

The measurement of the Electrical Fast Transient/Burst was investigated and test result was shown on the appendix A. The acceptance criterion was met and the EUT has passed the measurement.

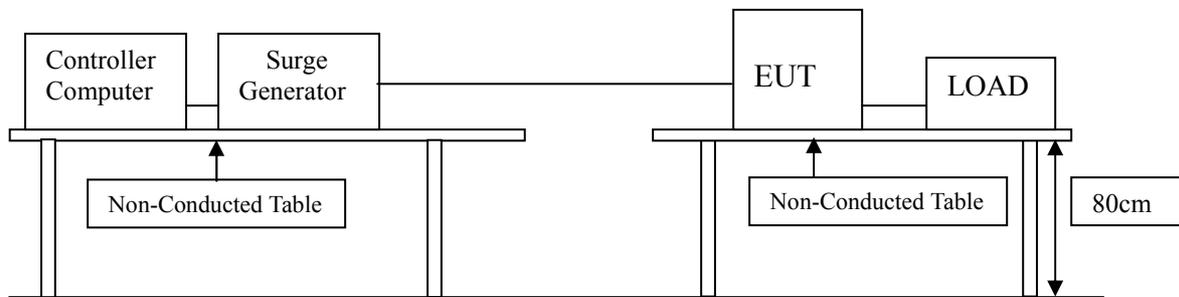
## 9. Surge

### 9.1 Test Equipment List

No	Instrument	Manufacture	Model	Serial No.	Last Calibrate
1.	EMC Test System	EMC Partner	Transient-1000	TR1000-341	Aug 15, 2001

Remark: All equipment upon which need to calibrated are with calibration period of one year.

### 9.2 Test Setup



### 9.3 Test Level

Item	Environment	Unit	Test Specification	Performance Criteria
<b>Dc Input and DC Output Power Ports</b>				
	Surge	Tr/Ts ( $\mu$ s)	1.2/50(8/20)	B
	Line to Ground	KV	$\pm 0.5$	
	Line to Line	KV	$\pm 0.5$	
<b>AC Input and AC Output Power Ports</b>				
	Surge	Tr/Ts ( $\mu$ s)	1.2/50(8/20)	B
	Line to Ground	KV	$\pm 4$	
	Line to Line	KV	$\pm 2$	

## 9.4 Test Procedure

The EUT and its load are placed on a table which is 0.8 meter height above a metal ground plane dimension is 1 meter x 1 meter and the thickness is 0.5 mm. It's also projected beyond the EUT at least 0.1 meter on all sides. The length of power cord between the coupling device and the EUT shall be 2meter or less.

For Input and Output AC Power or DC Input and Dc Output Power Ports:

The EUT is connected to the power mains through a coupling device that directly couples the Surge interference signal.

The Surge noise shall be applied synchronized to the voltage phase at 0°, 90°, 180°, 270° and the peak value of the AC voltage wave. (Positive and Negative)

Each of line-earth and line-line is impressed with a sequence of five surge voltages with interval of 1 minute.

## 9.5 Test Specification

According to EN 61000-4-5/1995

## 9.6 Test Result

The Measurement of the Surge was investigated and the test result was shown on the appendix A. The acceptance criterion was met and the EUT has passed the test.

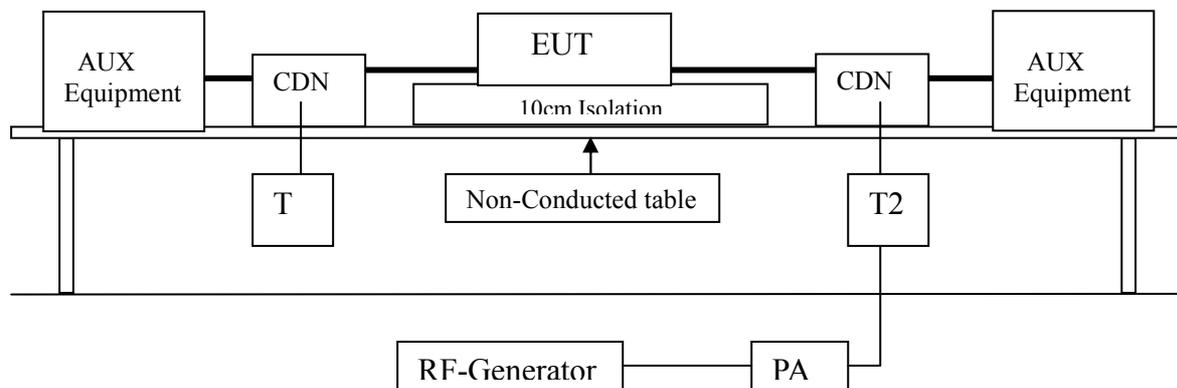
## 10. Conducted Susceptibility

### 10.1 Test Equipment List

No.	Instrument	Manufacture	Model	Serial No.	Last Calibrate
1.	Signal Generator	Rohde & Schwarz	SMY 02	845069/018	May 02, 2001
2.	Power Amplifier	Amplifier Research	100W1000M1A	20638	May 01, 2001
4.	Directional Coupler	Amplifier Research	DC2600	20508	Aug 23, 2001
5.	CDN	FCC	FCC-801-M3-25A	9993	Aug 23, 2001

Remark: All equipment upon which need to calibrated are with calibration period of one year.

### 10.2 Test Setup



### 10.3 Test Level

Item	Environment	Unit	Test Specification	Performance Criteria
Ports for Signal Lines and Data Buses, not involved in process control, etc.				
	Radio-Frequency	MHz		0.15 ~ 80
	Common Mode	V (rms, Unmodulated)		10
	Amplitude Modulated	%AM (1KHz)		80
		Source Impedance		150
Ac Input and AC Output and DC Input and DC output Ports and Functional Earth Ports				
	Radio-Frequency	MHz		0.15 ~ 80
	Common Mode	V (rms, Unmodulated)		10
	Amplitude Modulated	%AM (1KHz)		80
		Source Impedance		150

## 10.4 Test Procedure

The EUT are placed on a table which is 0.8meter height and a ground reference plane on the table, the EUT are placed upon table and use a 10cm insulation between the EUT and ground reference plane.

For AC Input and AC Output Power or DC Input and DC Output Power Ports:  
The EUT is connected to the power mains through a coupling and decoupling networks for power supply lines. It also directly couples the disturbance signal into EUT.  
Use CDN-M2 for two wires or CDN-3 for three wires.

For Signal Lines Lines and Control Lines Test:  
The disturbance signal is through a coupling and decoupling networks (CDN) or EM-clamp device couples to the signal and control lines of the EUT.

All scanning frequencies conditions are as following:

Condition of Test	Remarks:
1. Field Strength	10V, Level 3
2. Radiated Signal	AM 80% modulated with 1KHz
3. Scanning frequencies	0.15MHz ~ 80MHz
4. Dwell Time	3 seconds
5. Frequency step size $\Delta f$	1%
6. The rate of Swept of Frequency	$1.5 \times 10^{-3}$ decades/s

## 10.5 Test Specification

According to EN 61000-4-6/1996

## 10.6 Test Result

The Measurement of the Conducted Susceptibility was investigated and the test result was shown on the appendix A. The acceptance criterion was met and the EUT has passed the test.

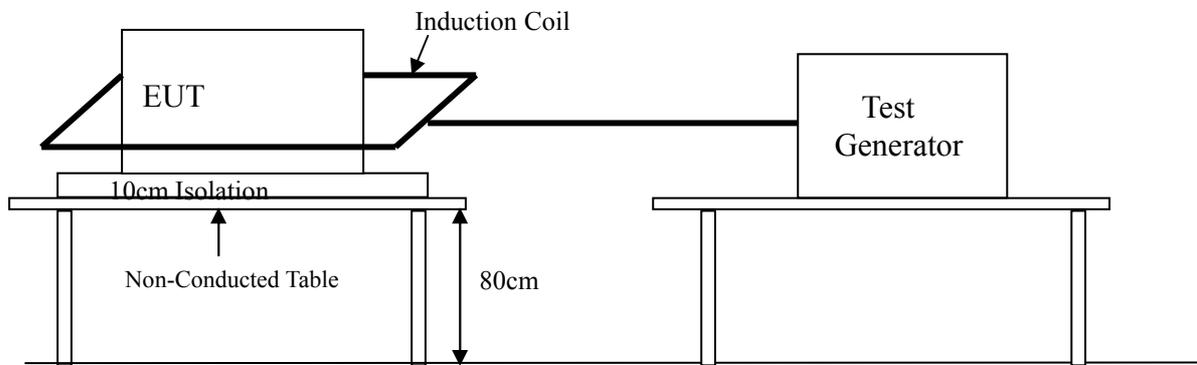
# 11 Power Frequency Magnetic Field

## 11.1 Test Equipment List

No.	Instrument	Manufacture	Model	Serial No.	Last Calibrate
1.	EMC Test System	EMC Partner	Transient-1000	TR1000-341	Aug 15, 2001
2.	Magnetic Coil	EMC Partner	MF-1000	MF1000-1-51	Aug 15, 2001

Remark: All equipment upon which need to calibrated are with calibration period of one year.

## 11.2 Test Setup



## 11.3 Test Level

Item	Environment	Unit	Test Specification	Performance Criteria
Enclosure Room				
Power-Frequency		50	Hz	A
Magnetic Field		30	A/M	

## 11.4 Test Procedure

The EUT and its load are placed on a table that is 0.8 meter above the metal ground plane dimension is at least 1 meter x 1 meter. The test magnetic field shall be placed at least than 3 meters distance from the induction coil.

The test magnetic field shall be applied by the immersion method to the EUT. The induction coil shall be rotated by 90° in order to expose the EUT to the test field with different orientation (X, Y, Z orientation).

## 11.5 Test Specification

According to EN 61000-4-8/1993

## 11.6 Test Result

The Measurement of the Power Frequency Magnetic Field was investigated and the test result was shown on the appendix A. The acceptance criterion was met and the EUT has passed the test.

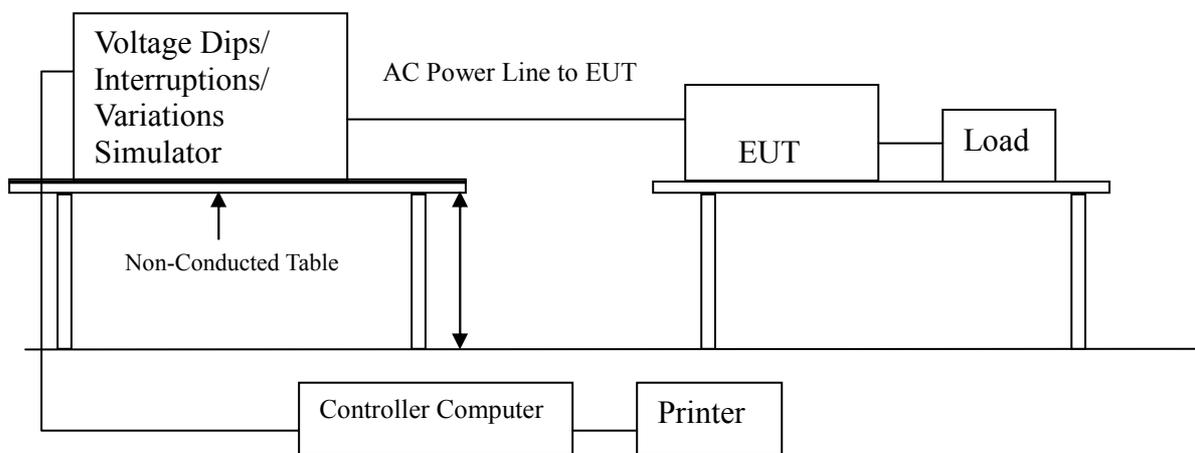
## 12. Voltage Dips and Interruption Measurement

### 12.1 Test Equipment List

No.	Instrument	Manufacture	Model	Serial No.	Last Calibrate
1.	EMC Test System	EMC Partner	Transient-1000	TR1000-341	Aug 15, 2001

Remark: All equipment upon which need to calibrated are with calibration period of one year.

### 12.2 Test setup



### 12.3 Test Level

Item	Environment	Unit	Test Specification	Performance Criteria
Ac Input and AC Output Power Ports				
Voltage Dips		30	% Reduction	B
		10	ms	
		60	% reduction	C
		100	ms	
		>95%	Reduction	C
Voltage Interruption		5000	ms	

## 12.4 Test Procedure

The EUT and its load are placed on a wooden table which is 0.8 meter above a metal ground plane which dimension is 1 meter x 1 meter, the thickness is 0.65mm. It projected beyond the EUT by at least 0.1 meter on all sides. The power cord shall be used the shortest power cord as specified by the manufacturer.

For Voltage Dips / Interruption Test:

The EUT is connected to the power mains through a coupling device that directly couples to the Voltage Dips and Interruption Generator.

The EUT shall be tested for 30% voltage dips of supplied voltage and duration time is 10ms, for 60% voltage dips of supplied voltage and duration time is 100ms with a sequence of three voltage dips with intervals of 10 seconds, and for 95% voltage interruption of supplied voltage and the duration time is 5000ms with a sequence of three voltage interruptions with intervals of 10 seconds.

Voltage phase shifting are shall occur at 0°, 45°, 90°, 135°, 180°, 225°, 270°, 315° of the voltage.

## 12.5 Test Specification

According to EN 61000-4-11/1994

## 12.6 Test Result

N / A

## **13 Modification List for EMC Complying Test**

The modification is solely made by the applicant.

## **14 Appendix**

Appendix A: Summary of Test Result

Appendix B: The test photograph of EUT

Appendix C: The Detail Photograph of EUT

## Appendix A: Summary of Test Result

The test result in the emission and immunity were performed according to the requirement of measurement standard and procedures. Best Laboratory is assumed full responsibility for the accuracy and completeness of these measurements. The Test data of the emissions and immunity are listed as the appendix data.

All these tests are were carried out with the EUT in normal operation, which was defined as:

**\*\*\*\*\* EMC Test Result: The EUT has been passed the all measurements. \*\*\*\*\***

The uncertainty is calculated in accordance with NAMAS NIS 81, the total uncertainty for this test is as follows:

⇒ Emission Test

- \* Uncertainty in the Conducted Emission Test: <±2.0dB
- \* Uncertainty in the Field Strength measurement: <±4.0dB

**Conducted Emission Test**

Date Measurement Performed: Mar. 28, 2002

EUT : Biscuit 486CPU-133 FSB-66 clock all-in-one LAN/VGA CPU card

Testing Mode : 640 x 480MHz, LAN=10MHz

Temperature : 26°C

Humidity : 73%RH

**Line 1:**

Frequency (KHz)	Corrected Amplitude (dB $\mu$ V)			Limit (dB $\mu$ V)		Margin dB
	Peak	QP	Avg.	QP	Avg.	
159.3500	55.71	***	***	79.00	66.00	-10.29
486.6000	50.72	***	***	79.00	66.00	-15.28
745.0000	47.62	***	***	73.00	60.00	-12.38
1220.0000	43.22	***	***	73.00	60.00	-16.78
1640.0000	37.99	***	***	73.00	60.00	-22.01
5015.0000	39.34	***	***	73.00	60.00	-20.66
12000.0000	51.93	***	***	73.00	60.00	-8.07
13408.0000	52.41	***	***	73.00	60.00	-7.59
18248.0000	39.80	***	***	73.00	60.00	-20.20
22168.0000	34.78	***	***	73.00	60.00	-25.22

**Line 2:**

Frequency (KHz)	Corrected Amplitude (dB $\mu$ V)			Limit (dB $\mu$ V)		Margin dB
	Peak	QP	Avg.	QP	Avg.	
172.9500	52.34	***	***	79.00	66.00	-13.66
477.2500	49.37	***	***	79.00	66.00	-16.63
563.1000	53.03	***	***	73.00	60.00	-6.97
836.8000	47.18	***	***	73.00	60.00	-12.82
1720.0000	43.45	***	***	73.00	60.00	-16.55
3265.0000	46.16	***	***	73.00	60.00	-13.84
4995.0000	39.42	***	***	73.00	60.00	-20.58
11992.0000	50.34	***	***	73.00	60.00	-9.66
13424.0000	51.63	***	***	73.00	60.00	-8.37
18240.0000	40.79	***	***	73.00	60.00	-19.21

\*\*\* Remark: The above corrected amplitudes are all under the average limit. \*\*\*

**Conducted Emission Test**

Date Measurement Performed: Mar. 28, 2002

EUT : Biscuit 486CPU-133 FSB-66 clock all-in-one LAN/VGA CPU card

Testing Mode : 800 x 600MHz, LAN=10MHz

Temperature : 26°C

Humidity : 73%RH

**Line 1:**

Frequency (KHz)	Corrected Amplitude (dB $\mu$ V)			Limit (dB $\mu$ V)		Margin dB
	Peak	QP	Avg.	QP	Avg.	
171.2500	57.20	***	***	79.00	66.00	-8.80
280.0500	50.95	***	***	79.00	66.00	-15.05
493.4000	49.75	***	***	79.00	66.00	-16.25
756.9000	50.35	***	***	73.00	60.00	-9.65
877.6000	47.26	***	***	73.00	60.00	-12.74
2175.0000	36.29	***	***	73.00	60.00	-23.71
8016.0000	41.34	***	***	73.00	60.00	-18.66
12000.0000	50.70	***	***	73.00	60.00	-9.30
13368.0000	52.17	***	***	73.00	60.00	-7.83
18920.0000	41.59	***	***	73.00	60.00	-18.41

**Line 2:**

Frequency (KHz)	Corrected Amplitude (dB $\mu$ V)			Limit (dB $\mu$ V)		Margin dB
	Peak	QP	Avg.	QP	Avg.	
188.2500	57.12	***	***	79.00	66.00	-8.88
259.6500	54.60	***	***	79.00	66.00	-11.40
342.1000	59.55	***	***	79.00	66.00	-6.45
554.6000	52.18	***	***	73.00	60.00	-7.82
958.3500	48.08	***	***	73.00	60.00	-11.92
1795.0000	42.55	***	***	73.00	60.00	-17.45
8008.0000	41.00	***	***	73.00	60.00	-19.00
11984.0000	50.42	***	***	73.00	60.00	-9.58
13408.0000	51.27	***	***	73.00	60.00	-8.73
18368.0000	39.80	***	***	73.00	60.00	-20.20

\*\*\* Remark: The above corrected amplitudes are all under the average limit. \*\*\*

**Conducted Emission Test**

Date Measurement Performed: Mar. 28, 2002

EUT : Biscuit 486CPU-133 FSB-66 clock all-in-one LAN/VGA CPU card

Testing Mode : 1024 x 768MHz, LAN=10MHz

Temperature : 26°C

Humidity : 73%RH

**Line 1:**

Frequency (KHz)	Corrected Amplitude (dB $\mu$ V)			Limit (dB $\mu$ V)		Margin dB
	Peak	QP	Avg.	QP	Avg.	
166.1500	63.17	***	***	79.00	66.00	-2.83
184.0000	61.04	***	***	79.00	66.00	-4.96
289.4000	58.37	***	***	79.00	66.00	-7.63
385.4500	56.98	***	***	79.00	66.00	-9.02
660.8500	52.37	***	***	73.00	60.00	-7.63
988.1000	51.60	***	***	73.00	60.00	-8.40
2740.0000	44.23	***	***	73.00	60.00	-15.77
11992.0000	51.27	***	***	73.00	60.00	-8.73
13376.0000	52.46	***	***	73.00	60.00	-7.54
19608.0000	41.48	***	***	73.00	60.00	-18.52

**Line 2:**

Frequency (KHz)	Corrected Amplitude (dB $\mu$ V)			Limit (dB $\mu$ V)		Margin dB
	Peak	QP	Avg.	QP	Avg.	
168.7000	57.77	***	***	79.00	66.00	-8.23
212.9000	56.29	***	***	79.00	66.00	-9.71
303.8500	51.49	***	***	79.00	66.00	-14.51
547.8000	50.71	***	***	73.00	60.00	-9.29
881.0000	51.86	***	***	73.00	60.00	-8.14
1270.0000	44.79	***	***	73.00	60.00	-15.21
2745.0000	39.30	***	***	73.00	60.00	-20.70
12008.0000	50.42	***	***	73.00	60.00	-9.58
13408.0000	51.32	***	***	73.00	60.00	-8.68
19584.0000	40.08	***	***	73.00	60.00	-19.92

\*\*\* Remark: The above corrected amplitudes are all under the average limit. \*\*\*

### Conducted Emission Test

Date Measurement Performed: Mar. 28, 2002

EUT : Biscuit 486CPU-133 FSB-66 clock all-in-one LAN/VGA CPU card  
 Testing Mode : 640 x 480MHz, LAN=100MHz  
 Temperature : 26°C  
 Humidity : 73%RH

**Line 1:**

Frequency (KHz)	Corrected Amplitude (dBµV)			Limit (dBµV)		Margin dB
	Peak	QP	Avg.	QP	Avg.	
159.3500	59.50	***	***	79.00	66.00	-6.50
198.4500	60.14	***	***	79.00	66.00	-5.86
235.0000	58.23	***	***	79.00	66.00	-7.77
325.1000	52.55	***	***	79.00	66.00	-13.45
524.0000	50.70	***	***	73.00	60.00	-9.30
1200.0000	46.39	***	***	73.00	60.00	-13.61
5010.0000	38.42	***	***	73.00	60.00	-21.58
12008.0000	51.13	***	***	73.00	60.00	-8.87
13416.0000	52.03	***	***	73.00	60.00	-7.97
18360.0000	41.81	***	***	73.00	60.00	-18.19

**Line 2:**

Frequency (KHz)	Corrected Amplitude (dBµV)			Limit (dBµV)		Margin dB
	Peak	QP	Avg.	QP	Avg.	
193.3500	62.58	***	***	79.00	66.00	-3.42
341.2500	54.60	***	***	79.00	66.00	-6.87
537.6000	54.30	***	***	73.00	60.00	-5.70
658.3000	56.00	***	***	73.00	60.00	-4.00
977.0500	54.18	***	***	73.00	60.00	-5.82
1970.0000	51.02	***	***	73.00	60.00	-8.98
3745.0000	45.64	***	***	73.00	60.00	-14.36
12000.0000	50.45	***	***	73.00	60.00	-9.55
13368.0000	51.26	***	***	73.00	60.00	-8.74
18896.0000	39.81	***	***	73.00	60.00	-20.19

\*\*\* Remark: The above corrected amplitudes are all under the average limit. \*\*\*

**Conducted Emission Test**

Date Measurement Performed: Mar. 28, 2002

EUT : Biscuit 486CPU-133 FSB-66 clock all-in-one LAN/VGA CPU card

Testing Mode : 800 x 600MHz, LAN=100MHz

Temperature : 26°C

Humidity : 73%RH

**Line 1:**

Frequency (KHz)	Corrected Amplitude (dB $\mu$ V)			Limit (dB $\mu$ V)		Margin dB
	Peak	QP	Avg.	QP	Avg.	
182.3000	51.82	***	***	79.00	66.00	-14.18
229.9000	50.30	***	***	79.00	66.00	-15.70
349.7500	47.52	***	***	79.00	66.00	-18.48
537.6000	49.87	***	***	73.00	60.00	-10.13
2685.0000	36.76	***	***	73.00	60.00	-23.24
7992.0000	41.60	***	***	73.00	60.00	-18.40
13416.0000	52.43	***	***	73.00	60.00	-7.57
14152.0000	51.06	***	***	73.00	60.00	-8.94
16216.0000	43.78	***	***	73.00	60.00	-16.22
18496.0000	39.39	***	***	73.00	60.00	-20.61

**Line 2:**

Frequency (KHz)	Corrected Amplitude (dB $\mu$ V)			Limit (dB $\mu$ V)		Margin dB
	Peak	QP	Avg.	QP	Avg.	
161.9000	55.62	***	***	79.00	66.00	-10.38
532.5000	50.87	***	***	73.00	60.00	-9.13
724.6000	45.98	***	***	73.00	60.00	-14.02
941.3500	56.13	***	***	73.00	60.00	-3.87
3095.0000	45.84	***	***	73.00	60.00	-14.16
6432.0000	42.56	***	***	73.00	60.00	-17.44
8008.0000	42.62	***	***	73.00	60.00	-17.38
13360.0000	51.23	***	***	73.00	60.00	-8.77
14176.0000	50.37	***	***	73.00	60.00	-9.63
18240.0000	38.48	***	***	73.00	60.00	-21.52

\*\*\* Remark: The above corrected amplitudes are all under the average limit. \*\*\*

**Conducted Emission Test**

Date Measurement Performed: Mar. 28, 2002

EUT : Biscuit 486CPU-133 FSB-66 clock all-in-one LAN/VGA CPU card

Testing Mode : 1024 x 768MHz, LAN=100MHz

Temperature : 26°C

Humidity : 73%RH

**Line 1:**

Frequency (KHz)	Corrected Amplitude (dB $\mu$ V)			Limit (dB $\mu$ V)		Margin dB
	Peak	QP	Avg.	QP	Avg.	
178.0500	52.18	***	***	79.00	66.00	-13.82
467.0500	56.48	***	***	79.00	66.00	-9.52
514.6500	53.78	***	***	73.00	60.00	-6.22
802.8000	50.33	***	***	73.00	60.00	-9.67
1020.0000	45.43	***	***	73.00	60.00	-14.57
2815.0000	40.48	***	***	73.00	60.00	-19.52
4155.0000	41.09	***	***	73.00	60.00	-18.91
13424.0000	52.07	***	***	73.00	60.00	-7.93
14160.0000	51.60	***	***	73.00	60.00	-8.40
19544.0000	39.58	***	***	73.00	60.00	-20.42

**Line 2:**

Frequency (KHz)	Corrected Amplitude (dB $\mu$ V)			Limit (dB $\mu$ V)		Margin dB
	Peak	QP	Avg.	QP	Avg.	
160.2000	53.70	***	***	79.00	66.00	-12.30
228.2000	55.55	***	***	79.00	66.00	-10.45
527.4000	50.75	***	***	73.00	60.00	-9.25
993.2000	46.20	***	***	73.00	60.00	-13.80
1635.0000	44.55	***	***	73.00	60.00	-15.45
5050.0000	40.98	***	***	73.00	60.00	-19.02
13384.0000	51.29	***	***	73.00	60.00	-8.71
14176.0000	50.05	***	***	73.00	60.00	-9.95
18248.0000	38.12	***	***	73.00	60.00	-21.88
22192.0000	34.41	***	***	73.00	60.00	-25.59

\*\*\* Remark: The above corrected amplitudes are all under the average limit. \*\*\*

## Field Strength Test

Date Measurement Performed: Mar. 30, 2002

EUT : Biscuit 486CPU-133 FSB-66 clock all-in-one LAN/VGA CPU card  
 Testing Mode : 800 x 600MHz, LAN=100MHz  
 Polarity : Vertical  
 Temperature : 26°C  
 Humidity : 77%RH

Frequency (MHz)	Reading Amplitude (dBμV/m)	Table Degree (°)	Antenna Height (Meter)	Correction Factor (dB/m)	Corrected Amplitude (dBμV/m)	Limit (dBμV/m)	Margin (dB)
48.038	14.96	53	1.00	8.91	23.87	40.00	-16.13
69.111	21.29	224	1.00	6.80	28.09	40.00	-11.91
168.073	10.37	176	1.00	10.47	20.83	40.00	-19.17
207.366	10.79	60	1.00	10.14	20.93	40.00	-19.07
257.708	12.95	31	1.00	14.56	27.51	47.00	-19.49
386.578	17.00	262	1.00	16.38	33.37	47.00	-13.63
***							

Remark:

1. The “ Correction Factor “ contains antenna factor, cable loss.
2. The formula of “ Corrected Amplitude “ is as follow”  
 Reading Amplitude + Correction Factor = Corrected Amplitude.

## Field Strength Measurement

Date Measurement Performed: Mar. 30, 2002

EUT : Biscuit 486CPU-133 FSB-66 clock all-in-one LAN/VGA CPU card  
 Testing Mode : 1024 x 768MHz, LAN=10MHz  
 Polarity : Horizontal  
 Temperature : 25°C  
 Humidity : 64%RH

Frequency (MHz)	Reading Amplitude (dBµV/m)	Table Degree (°)	Antenna Height (Meter)	Correction Factor (dB/m)	Corrected Amplitude (dBµV/m)	Limit (dBµV/m)	Margin (dB)
32.998	7.30	89	4.00	17.27	24.57	40.00	-15.43
48.110	5.41	359	3.99	8.87	14.28	40.00	-25.72
257.736	17.59	340	4.00	14.57	32.16	47.00	-14.84
386.574	18.60	193	2.50	2.50	16.38	47.00	-12.02
***							

Remark:

1. The “ Correction Factor “ contains antenna factor, cable loss.
2. The formula of “ Corrected Amplitude “ is as follow”  
 Reading Amplitude + Correction Factor = Corrected Amplitude.



## Electrostatic Discharge Test

Item	Amount of Discharge	Voltage	Required Criteria	Complied to Criteria	Results
Air Discharge	10	+2KV	B	B	Pass
	10	-2KV	B	B	Pass
	10	+4KV	B	B	Pass
	10	-4KV	B	B	Pass
	10	+8KV	B	B	Pass
	10	-8KV	B	B	Pass
Contact Discharge	25	+2KV	B	B	Pass
	25	-2KV	B	B	Pass
	25	-4KV	B	B	Pass
	25	-4KV	B	B	Pass
Indirect Discharge	25	+2KV	B	B	Pass
	25	-2KV	B	B	Pass
	25	+4KV	B	B	Pass
	25	-4KV	B	B	Pass

### Remark:

- Criteria A: Operation as intended during and after the measurement
- Criteria B: Operation as Intended after the test
- Criteria C: Malfunction during and after, need manual reset
- Criteria D: The sample is damaged

## Radiated Susceptibility

Frequency (MHz)	Position (Angle)	Polarity (H or V)	Field Strength (V/m)	Required Criteria	Complied Criteria	Result
80 ~ 1000	0	H	10	A	A	Pass
80 ~ 1000	0	V	10	A	A	Pass
80 ~ 1000	90	H	10	A	A	Pass
80 ~ 1000	90	V	10	A	A	Pass
80 ~ 1000	180	H	10	A	A	Pass
80 ~ 1000	180	V	10	A	A	Pass
80 ~ 1000	270	H	10	A	A	Pass
80 ~ 1000	270	V	10	A	A	Pass

### Remark:

- Criteria A: Operation as intended during and after the measurement
- Criteria B: Operation as Intended after the test
- Criteria C: Malfunction during and after, need manual reset
- Criteria D: The sample is damaged

**Electrical Fast Transient / Burst**

Inject Line	Polarity	Voltage (KV)	Inject Time (Second)	Inject Method	Required Criteria	Complied Criteria	Result
L	±	2KV	60	Direct	B	B	Pass
N	±	2KV	60	Direct	B	B	Pass
PE	±	2KV	60	Direct	B	B	Pass
L+N	±	2KV	60	Direct	B	B	Pass
L+PE	±	2KV	60	Direct	B	B	Pass
N+PE	±	2KV	60	Direct	B	B	Pass
L+N+PE	±	2KV	60	Direct	B	B	Pass
Clamp	±	1KV	60	Couple	B	B	Pass

## Remark:

- Criteria A: Operation as intended during and after the measurement
- Criteria B: Operation as Intended after the test
- Criteria C: Malfunction during and after, need manual reset
- Criteria D: The sample is damaged

## Surge Test

Inject Line	Polarity	Angle	Voltage (KV)	Inject Time (Second)	Inject Method	Required Criteria	Complied Criteria	Result
L+N	±	0	1KV	60	Direct	B	B	Pass
L+N	±	90	1KV	60	Direct	B	B	Pass
L+N	±	180	1KV	60	Direct	B	B	Pass
L+N	±	270	1KV	60	Direct	B	B	Pass
L+PE	±	0	2KV	60	Direct	B	B	Pass
L+PE	±	90	2KV	60	Direct	B	B	Pass
L+PE	±	180	2KV	60	Direct	B	B	Pass
L+PE	±	270	2KV	60	Direct	B	B	Pass
N+PE	±	0	2KV	60	Direct	B	B	Pass
N+PE	±	90	2KV	60	Direct	B	B	Pass
N+PE	±	180	2KV	60	Direct	B	B	Pass
N+PE	±	270	2KV	60	Direct	B	B	Pass

### Remark:

- Criteria A: Operation as intended during and after the measurement
- Criteria B: Operation as Intended after the test
- Criteria C: Malfunction during and after, need manual reset
- Criteria D: The sample is damaged

## Conducted Susceptibility

Inject Line	Field Strength V	Inject Method	Required Criteria	Complied Criteria	Result
AC Line	10V	CDN	A	A	Pass
Data Cable	10V	CDN	A	A	Pass

Remark:

- Criteria A: Operation as intended during and after the measurement
- Criteria B: Operation as Intended after the test
- Criteria C: Malfunction during and after, need manual reset
- Criteria D: The sample is damaged

## Power Frequency Magnetic Field Test

Polarization	Frequency (Hz)	Magnetic Strength (A/M)	Required Criteria	Complied Criteria	Result
X Orientation	50	30	A	A	Pass
Y Orientation	50	30	A	A	Pass
Z Orientation	50	30	A	A	Pass

Remark:

- Criteria A: Operation as intended during and after the measurement
- Criteria B: Operation as Intended after the test
- Criteria C: Malfunction during and after, need manual reset
- Criteria D: The sample is damaged

## Voltage Dips and Interruption Test

Voltage Dips and Interruption Reduction (%)	Angle (Degree)	Test Duration (ms)	Required Criteria	Complied Criteria	Result
DIP					
30	0	10	B	B	Pass
30	45	10	B	B	Pass
30	90	10	B	B	Pass
30	135	10	B	B	Pass
30	180	10	B	B	Pass
30	225	10	B	B	Pass
30	270	10	B	B	Pass
30	315	10	B	B	Pass
60	0	100	C	C	Pass
60	45	100	C	C	Pass
60	90	100	C	C	Pass
60	135	100	C	C	Pass
60	180	100	C	C	Pass
60	225	100	C	C	Pass
60	270	100	C	C	Pass
60	315	100	C	C	Pass
Interruption					
>95	0	5000	C	C	Pass
>95	45	5000	C	C	Pass
>95	90	5000	C	C	Pass
>95	135	5000	C	C	Pass
>95	180	5000	C	C	Pass
>95	225	5000	C	C	Pass
>95	270	5000	C	C	Pass
>95	315	5000	C	C	Pass

### Remark:

- Criteria A: Operation as intended during and after the measurement
- Criteria B: Operation as Intended after the test (Test Mode: 30%)
- Criteria C: Malfunction during and after, need manual reset(Test Mode: 60%, >95%)
- Criteria D: The sample is damaged

## Appendix B: The Test Photograph of EUT

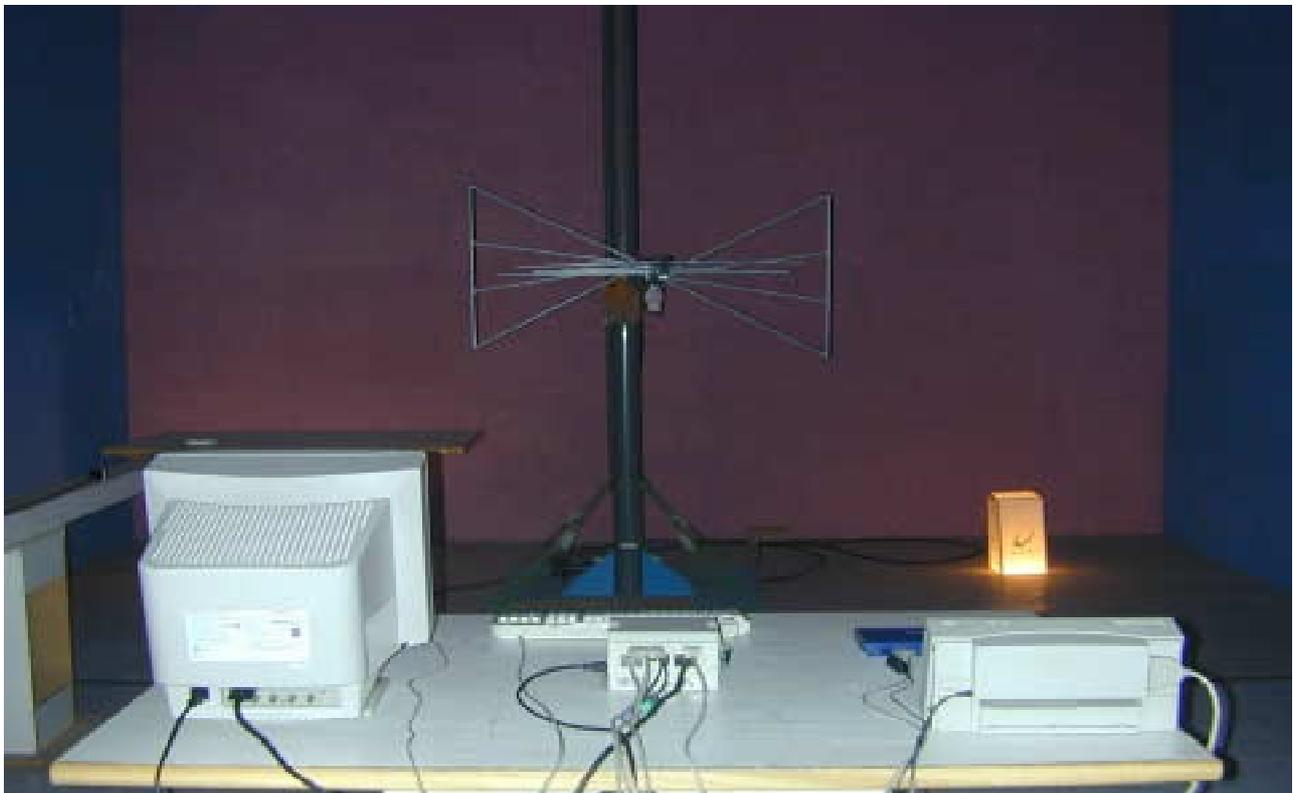
The Photograph of Conducted Emission Test --- Mains Port



The Photograph of Radiated Emission Test



### The Photograph of Radiation Susceptibility Test



The Photograph of Electrical Fast Transient/Burst Test



The Photograph of Electrostatic Discharge Test



### The Photograph of Surge Test

### The Photograph of Conducted Susceptibility Test



The Photograph of Power Frequency Magnetic Field Test



The Photograph of Voltage Dips and Interruption Test

## Appendix C: The Detail Photograph of EUT

